Search Notes

1	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/730,790	TUSZYNSKI ET	AL.
I	Examiner	Art Unit	
	Shin-Lin Chen	1632	

SEARCHED					
Class	Subclass	Date	Examiner		
514	44				
435	320.1				
435	455				
424	93.2				
424	93.21				
536	23.5	8/17/2006	4º		
-					

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
514	44		
435	320.1		
435	455		
424/93.2, 93.21; 536/23.5, AU interference search		8/17/2006	gu

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Updated, inventor name search.	8/17/2006	Gr.		